


<b>Search Notes</b>  	<b>Application/Control No.</b>  10617526	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN ET AL.
	<b>Examiner</b>  Neway, Samuel G	<b>Art Unit</b>  2626

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST: Text Search, PLUS Search	12/21/06	SN
EAST: Inventor, Assignee Search	12/21/06	SN
Consulted: John Peng, QAS, for 101, 112 issues	01/09/07	SN
Consulted: Talivaldis Smits, AU 2626	01/09/07	SN

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>